


<b>Search Notes</b>  	<b>Application/Control No.</b>  10628029	<b>Applicant(s)/Patent Under Reexamination</b>  NONAKA, TAKAAKI
	<b>Examiner</b>  MARK A FLEISCHER	<b>Art Unit</b>  4143

SEARCHED			
Class	Subclass	Date	Examiner
705	8	Dec. 14, 2007	MAF
705	7	Dec. 14, 2007	MAF
705	1	Dec. 14, 2007	MAF

SEARCH NOTES		
Search Notes	Date	Examiner
Reviewed US Pat 6151583	Dec. 14, 2007	MAF
Searched JP 10134127 A; JP 2000137763; DE 10105623 A; JP 10105623 A; JP 10134127 A	Dec. 14, 2007	MAF

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner